## **猷RANSMITTAL OF FORMAL DRAWINGS**

Docket No. **SLA0693** 

David R. Evans, Sheng Teng Hsu, Bruce D. Ulrich, Douglas J. Tweet and Lisa H. Stecker

Serial No.	Filing Date	Batch No.	Examiner	Art Unit
10/606,105	06/25/2003		Lynne Ann Gurley	2812

Invention: Self-Aligned Shallow Trench Isolation Process Having Improved Polysilicon Gate Thickness Control

Address to:

**Assistant Commissioner for Patents** Washington, D.C. 20231

Transmitted herewith are:

6 sheets of formal drawing(s) for this application.

Each sheet of drawing indicates the identifying indicia suggested in 37 CFR Section 1.84(c) on the reverse side of the drawing.

Signature

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I certify that this document and attached formal drawings are being deposited/on December 23 2003 with the U.S. Postal Service as first class mail under 37 C.F.R. 1.8 and addressed to the Assistant Commissioner for Patents,

Washington, D.C. 202

Signature of Person Mailing Correspondence

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